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# M24C16, M24C08 M24C04, M24C02, M24C01

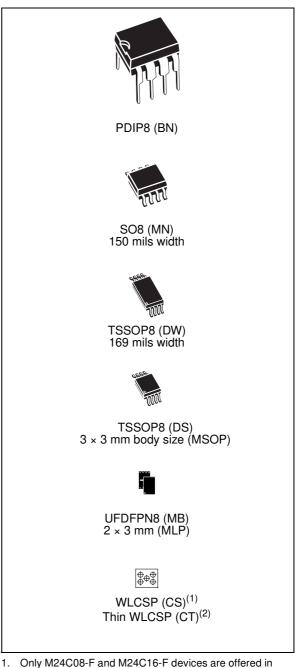
### 16 Kbit, 8 Kbit, 4 Kbit, 2 Kbit and 1 Kbit serial I2C bus EEPROM

#### **Features**

- Supports both the 100 kHz I<sup>2</sup>C Standard-mode and the 400 kHz I<sup>2</sup>C Fast-mode
- Single supply voltage:
  - 2.5 V to 5.5 V for M24Cxx-W
  - 1.8 V to 5.5 V for M24Cxx-R
  - 1.7 V to 5.5 V for M24Cxx-F
- Write Control input
- Byte and Page Write (up to 16 bytes)
- Random and Sequential Read modes
- Self-timed programming cycle
- Automatic address incrementing
- Enhanced ESD/latch-up protection
- More than 1 million write cycles
- More than 40-year data retention
- Packages
  - ECOPACK<sup>®</sup> (RoHS compliant)

Table 1. Device summary

Reference	Part number
	M24C16-W
M24C16	M24C16-R
	M24C16-F
	M24C08-W
M24C08	M24C08-R
	M24C08-F
	M24C04-W
M24C04	M24C04-R
	M24C04-F
M24C02	M24C02-W
10124002	M24C02-R
M24C01	M24C01-W
M24C01	M24C01-R



- the WLCSP package.
- 2. Only M24C08-F devices are offered in the Thin WLCSP package.

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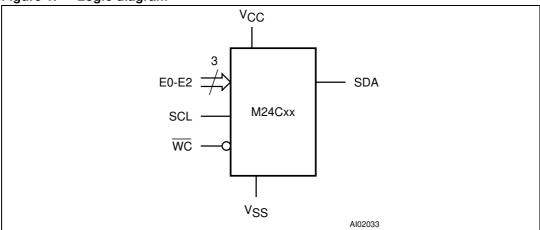
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### 1 Description

These I<sup>2</sup>C-compatible electrically erasable programmable memory (EEPROM) devices are organized as 2048/1024/512/256/128 x 8 (M24C16, M24C08, M24C04, M24C02 and M24C01).

Figure 1. Logic diagram



I<sup>2</sup>C uses a two-wire serial interface, comprising a bidirectional data line and a clock line. The devices carry a built-in 4-bit Device Type Identifier code (1010) in accordance with the I<sup>2</sup>C bus definition.

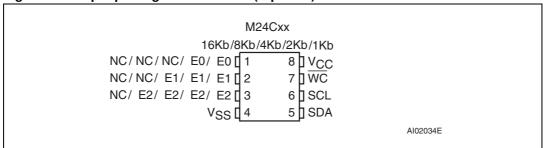
The device behaves as a slave in the  $I^2C$  protocol, with all memory operations synchronized by the serial clock. Read and Write operations are initiated by a Start condition, generated by the bus master. The Start condition is followed by a device select code and Read/Write bit (RW) (as described in *Table 3*), terminated by an acknowledge bit.

When writing data to the memory, the device inserts an acknowledge bit during the 9<sup>th</sup> bit time, following the bus master's 8-bit transmission. When data is read by the bus master, the bus master acknowledges the receipt of the data byte in the same way. Data transfers are terminated by a Stop condition after an Ack for Write, and after a NoAck for Read.

Table 2. Signal names

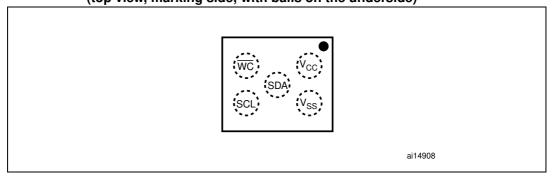
Signal name	Function	Direction	
E0, E1, E2	Chip Enable	Input	
SDA	Serial Data	Input/output	
SCL	Serial Clock	Input	
WC	Write Control	Input	
V <sub>CC</sub>	Supply voltage		
V <sub>SS</sub>	Ground		

Figure 2. 8-pin package connections (top view)



- 1. NC = Not connected
- 2. See Section 7: Package mechanical data for package dimensions, and how to identify pin-1.

Figure 3. M24C08-F WLCSP and thin WLCSP connections (top view, marking side, with balls on the underside)



### 2 Signal description

### 2.1 Serial Clock (SCL)

This input signal is used to strobe all data in and out of the device. In applications where this signal is used by slave devices to synchronize the bus to a slower clock, the bus master must have an open drain output, and a pull-up resistor can be connected from Serial Clock (SCL) to  $V_{CC}$ . (*Figure 5* indicates how the value of the pull-up resistor can be calculated). In most applications, though, this method of synchronization is not employed, and so the pull-up resistor is not necessary, provided that the bus master has a push-pull (rather than open drain) output.

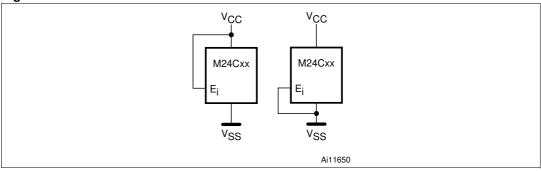
### 2.2 Serial Data (SDA)

This bidirectional signal is used to transfer data in or out of the device. It is an open drain output that may be wire-ORed with other open drain or open collector signals on the bus. A pull up resistor must be connected from Serial Data (SDA) to V<sub>CC</sub>. (*Figure 5* indicates how the value of the pull-up resistor can be calculated).

### 2.3 Chip Enable (E0, E1, E2)

These input signals are used to set the value that is to be looked for on the three least significant bits (b3, b2, b1) of the 7-bit device select code. These inputs must be tied to  $V_{CC}$  or  $V_{SS}$ , to establish the device select code as shown in *Figure 4*. When not connected (left floating), E0, E1, E2 are read as low (0,0,0).

Figure 4. Device select code



### 2.3.1 Write Control (WC)

This input signal is useful for protecting the entire contents of the memory from inadvertent write operations. Write operations are disabled to the entire memory array when Write Control ( $\overline{WC}$ ) is driven High. When unconnected, the signal is internally read as  $V_{IL}$ , and Write operations are allowed.

When Write Control ( $\overline{WC}$ ) is driven High, device select and address bytes are acknowledged, data bytes are not acknowledged.

### 2.4 Supply voltage (V<sub>CC</sub>)

### 2.4.1 Operating supply voltage V<sub>CC</sub>

Prior to selecting the memory and issuing instructions to it, a valid and stable  $V_{CC}$  voltage within the specified [ $V_{CC}$ (min),  $V_{CC}$ (max)] range must be applied (see *Table 6*, *Table 7* and *Table 8*). In order to secure a stable DC supply voltage, it is recommended to decouple the  $V_{CC}$  line with a suitable capacitor (usually of the order of 10 nF to 100 nF) close to the  $V_{CC}/V_{SS}$  package pins.

This voltage must remain stable and valid until the end of the transmission of the instruction and, for a Write instruction, until the completion of the internal write cycle (t<sub>W</sub>).

#### 2.4.2 Power-up conditions

The  $V_{CC}$  voltage has to rise continuously from 0 V up to the minimum  $V_{CC}$  operating voltage defined in *Table 6*, *Table 7* and *Table 8* and the rise time must *not* vary faster than 1 V/µs.

#### 2.4.3 Device reset

In order to prevent inadvertent write operations during power-up, a power-on-reset (POR) circuit is included. At power-up (continuous rise of  $V_{CC}$ ), the device does not respond to any instruction until  $V_{CC}$  reaches the power-on-reset threshold voltage (this threshold is lower than the minimum  $V_{CC}$  operating voltage defined in *Table 6*, *Table 7* and *Table 8*). When  $V_{CC}$  passes over the POR threshold, the device is reset and enters the Standby Power mode. The device, however, must not be accessed until  $V_{CC}$  reaches a valid and stable  $V_{CC}$  voltage within the specified  $[V_{CC}(min), V_{CC}(max)]$  range.

In a similar way, during power-down (continuous decrease in  $V_{CC}$ ), as soon as  $V_{CC}$  drops below the power-on-reset threshold voltage, the device stops responding to any instruction sent to it.

#### 2.4.4 Power-down conditions

During power-down (continuous decrease in  $V_{CC}$ ), the device must be in the Standby Power mode (mode reached after decoding a Stop condition, assuming that there is no internal write cycle in progress).

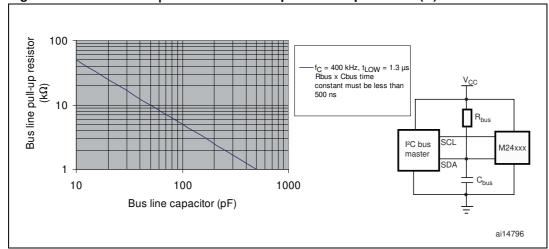


Figure 5. Maximum R<sub>P</sub> value versus bus parasitic capacitance (C) for an I<sup>2</sup>C bus



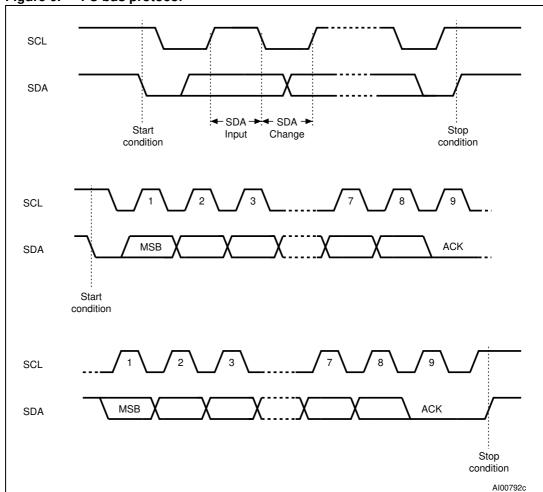


Table 3. Device select code

	Device type identifier <sup>(1)</sup>					Chip Enable <sup>(2),(3)</sup>			
	b7	b6	b5	b4	b3	b2	b1	b0	
M24C01 select code	1	0	1	0	E2	E1	E0	R₩	
M24C02 select code	1	0	1	0	E2	E1	E0	R₩	
M24C04 select code	1	0	1	0	E2	E1	A8	R₩	
M24C08 select code	1	0	1	0	E2	A9	A8	R₩	
M24C16 select code	1	0	1	0	A10	A9	A8	RW	

<sup>1.</sup> The most significant bit, b7, is sent first.

<sup>2.</sup> E0, E1 and E2 are compared against the respective external pins on the memory device.

<sup>3.</sup> A10, A9 and A8 represent most significant bits of the address.

### 3 Device operation

The device supports the I<sup>2</sup>C protocol. This is summarized in *Figure 6*. Any device that sends data on to the bus is defined to be a transmitter, and any device that reads the data to be a receiver. The device that controls the data transfer is known as the bus master, and the other as the slave device. A data transfer can only be initiated by the bus master, which will also provide the serial clock for synchronization. The M24Cxx device is always a slave in all communication.

#### 3.1 Start condition

Start is identified by a falling edge of Serial Data (SDA) while Serial Clock (SCL) is stable in the High state. A Start condition must precede any data transfer command. The device continuously monitors (except during a Write cycle) Serial Data (SDA) and Serial Clock (SCL) for a Start condition, and will not respond unless one is given.

### 3.2 Stop condition

Stop is identified by a rising edge of Serial Data (SDA) while Serial Clock (SCL) is stable and driven High. A Stop condition terminates communication between the device and the bus master. A Read command that is followed by NoAck can be followed by a Stop condition to force the device into the Standby mode. A Stop condition at the end of a Write command triggers the internal Write cycle.

### 3.3 Acknowledge bit (ACK)

The acknowledge bit is used to indicate a successful byte transfer. The bus transmitter, whether it be bus master or slave device, releases Serial Data (SDA) after sending eight bits of data. During the 9<sup>th</sup> clock pulse period, the receiver pulls Serial Data (SDA) Low to acknowledge the receipt of the eight data bits.

### 3.4 Data input

During data input, the device samples Serial Data (SDA) on the rising edge of Serial Clock (SCL). For correct device operation, Serial Data (SDA) must be stable during the rising edge of Serial Clock (SCL), and the Serial Data (SDA) signal must change *only* when Serial Clock (SCL) is driven Low.

### 3.5 Memory addressing

To start communication between the bus master and the slave device, the bus master must initiate a Start condition. Following this, the bus master sends the device select code, shown in *Table 3* (on Serial Data (SDA), most significant bit first).

The device select code consists of a 4-bit Device Type Identifier, and a 3-bit Chip Enable "Address" (E2, E1, E0). To address the memory array, the 4-bit Device Type Identifier is 1010b.

Each device is given a unique 3-bit code on the Chip Enable (E0, E1, E2) inputs. When the device select code is received, the device only responds if the Chip Enable Address is the same as the value on the Chip Enable (E0, E1, E2) inputs. However, those devices with larger memory capacities (the M24C16, M24C08 and M24C04) need more address bits. E0 is not available for use on devices that need to use address line A8; E1 is not available for devices that need to use address line A9, and E2 is not available for devices that need to use address line A10 (see *Figure 2* and *Table 3* for details). Using the E0, E1 and E2 inputs, up to eight M24C02 (or M24C01), four M24C04, two M24C08 or one M24C16 devices can be connected to one I²C bus. In each case, and in the hybrid cases, this gives a total memory capacity of 16 Kbits, 2 KBytes (except where M24C01 devices are used).

The 8<sup>th</sup> bit is the Read/Write bit (RW). This bit is set to 1 for Read and 0 for Write operations.

If a match occurs on the device select code, the corresponding device gives an acknowledgment on Serial Data (SDA) during the 9<sup>th</sup> bit time. If the device does not match the device select code, it deselects itself from the bus, and goes into Standby mode.

Table 4. Operating modes

Mode	R₩ bit	WC <sup>(1)</sup>	Bytes	Initial sequence	
Current Address Read	1	Х	1 Start, Device Select, RW = 1		
Random Address Read	0	Х	Start, Device Select, RW = 0, Addre		
nandom Address nead	1	Х	'	reStart, Device Select, $R\overline{W} = 1$	
Sequential Read	1	Х	≥ 1	Similar to Current or Random Address Read	
Byte Write	0	V <sub>IL</sub>	1 Start, Device Select, $R\overline{W} = 0$		
Page Write	0	V <sub>IL</sub>	≤ 16	Start, Device Select, $R\overline{W} = 0$	

<sup>1.</sup>  $X = V_{IH}$  or  $V_{IL}$ .

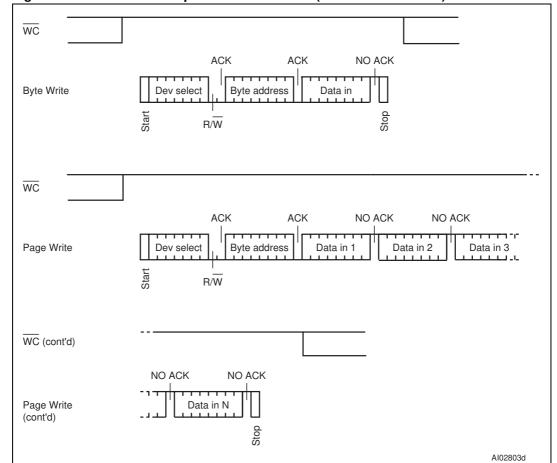


Figure 7. Write mode sequences with  $\overline{WC} = 1$  (data write inhibited)

### 3.6 Write operations

Following a Start condition the bus master sends a device select code with the Read/ $\overline{\text{Write}}$  bit ( $\overline{\text{RW}}$ ) reset to 0. The device acknowledges this, as shown in *Figure 8*, and waits for an address byte. The device responds to the address byte with an acknowledge bit, and then waits for the data byte.

When the bus master generates a Stop condition immediately after the Ack bit (in the "10<sup>th</sup> bit" time slot), either at the end of a Byte Write or a Page Write, the internal Write cycle is triggered. A Stop condition at any other time slot does not trigger the internal Write cycle.

During the internal Write cycle, Serial Data (SDA) and Serial Clock (SCL) are ignored, and the device does not respond to any requests.

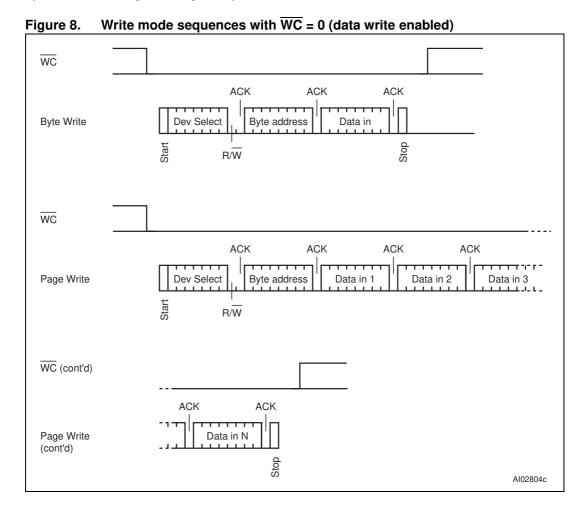
#### 3.6.1 Byte Write

After the device select code and the address byte, the bus master sends one data byte. If the addressed location is Write-protected, by Write Control ( $\overline{WC}$ ) being driven High (during the period from the Start condition until the end of the address byte), the device replies to the data byte with NoAck, as shown in *Figure 7*, and the location is not modified. If, instead, the addressed location is not Write-protected, the device replies with Ack. The bus master terminates the transfer by generating a Stop condition, as shown in *Figure 8*.

#### 3.6.2 Page Write

The Page Write mode allows up to 16 bytes to be written in a single Write cycle, provided that they are all located in the same page in the memory: that is, the most significant memory address bits are the same. If more bytes are sent than will fit up to the end of the page, a condition known as 'roll-over' occurs. This should be avoided, as data starts to become overwritten in an implementation dependent way.

The bus master sends from 1 to 16 bytes of data, each of which is acknowledged by the device if Write Control ( $\overline{WC}$ ) is Low. If the addressed location is Write-protected, by Write Control ( $\overline{WC}$ ) being driven High (during the period from the Start condition until the end of the address byte), the device replies to the data bytes with NoAck, as shown in *Figure 7*, and the locations are not modified. After each byte is transferred, the internal byte address counter (the 4 least significant address bits only) is incremented. The transfer is terminated by the bus master generating a Stop condition.



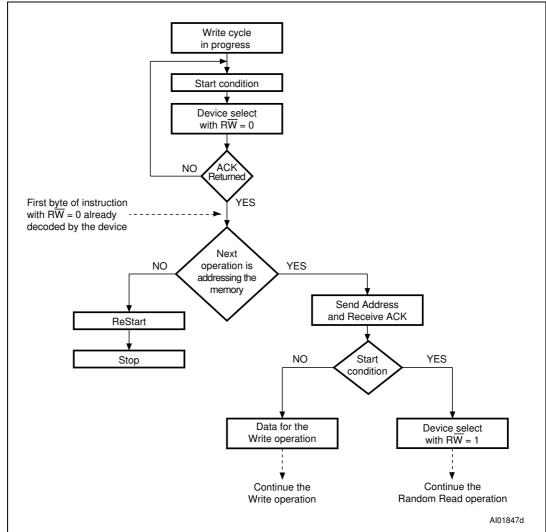


Figure 9. Write cycle polling flowchart using ACK

#### 3.6.3 Minimizing system delays by polling on ACK

During the internal Write cycle, the device disconnects itself from the bus, and writes a copy of the data from its internal latches to the memory cells. The maximum Write time  $(t_w)$  is shown in *Table 15*, but the typical time is shorter. To make use of this, a polling sequence can be used by the bus master.

The sequence, as shown in Figure 9, is:

- Initial condition: a Write cycle is in progress.
- Step 1: the bus master issues a Start condition followed by a device select code (the first byte of the new instruction).
- Step 2: if the device is busy with the internal Write cycle, no Ack will be returned and the bus master goes back to Step 1. If the device has terminated the internal Write cycle, it responds with an Ack, indicating that the device is ready to receive the second part of the instruction (the first byte of this instruction having been sent during Step 1).

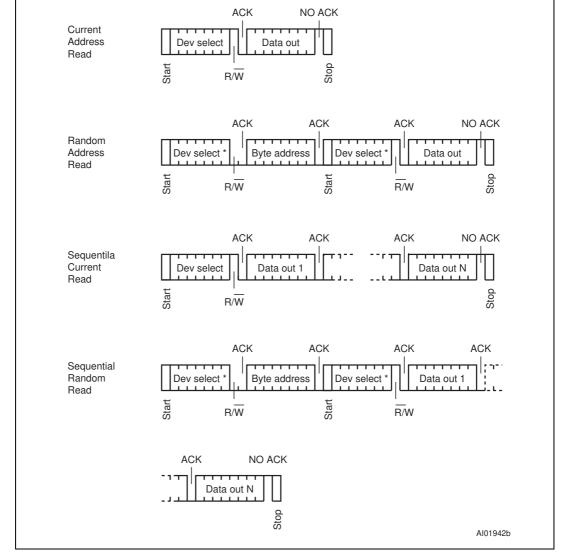


Figure 10. Read mode sequences

### 3.7 Read operations

Read operations are performed independently of the state of the Write Control ( $\overline{WC}$ ) signal. The device has an internal address counter which is incremented each time a byte is read.

#### 3.7.1 Random Address Read

A dummy Write is first performed to load the address into this address counter (as shown in *Figure 10*) but *without* sending a Stop condition. Then, the bus master sends another Start condition, and repeats the device select code, with the Read/Write bit (RW) set to 1. The device acknowledges this, and outputs the contents of the addressed byte. The bus master must *not* acknowledge the byte, and terminates the transfer with a Stop condition.

The seven most significant bits of the device select code of a Random Read (in the 1<sup>st</sup> and 3<sup>rd</sup> bytes) must be identical.

#### 3.7.2 Current Address Read

For the Current Address Read operation, following a Start condition, the bus master only sends a device select code with the Read/Write bit (RW) set to 1. The device acknowledges this, and outputs the byte addressed by the internal address counter. The counter is then incremented. The bus master terminates the transfer with a Stop condition, as shown in *Figure 10*, *without* acknowledging the byte.

#### 3.7.3 Sequential Read

This operation can be used after a Current Address Read or a Random Address Read. The bus master *does* acknowledge the data byte output, and sends additional clock pulses so that the device continues to output the next byte in sequence. To terminate the stream of bytes, the bus master must *not* acknowledge the last byte, and *must* generate a Stop condition, as shown in *Figure 10*.

The output data comes from consecutive addresses, with the internal address counter automatically incremented after each byte output. After the last memory address, the address counter 'rolls-over', and the device continues to output data from memory address 00h.

#### 3.7.4 Acknowledge in Read mode

For all Read commands, the device waits, after each byte read, for an acknowledgment during the 9<sup>th</sup> bit time. If the bus master does not drive Serial Data (SDA) Low during this time, the device terminates the data transfer and switches to its Standby mode.

# 4 Initial delivery state

The device is delivered with all bits in the memory array set to 1 (each byte contains FFh).

## 5 Maximum rating

Stressing the device outside the ratings listed in *Table 5* may cause permanent damage to the device. These are stress ratings only, and operation of the device at these, or any other conditions outside those indicated in the operating sections of this specification, is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Refer also to the STMicroelectronics SURE program and other relevant quality documents.

Table 5. Absolute maximum ratings

Symbol	Parameter	Min.	Max.	Unit
T <sub>A</sub>	Ambient operating temperature	-40	130	C
T <sub>STG</sub>	Storage temperature	<del>-</del> 65	150	S.
Lead temperature during soldering		see note (1)		S.
T <sub>LEAD</sub>	PDIP-specific lead temperature during soldering		260 <sup>(2)</sup>	℃
I <sub>OL</sub>	DC output current (SDA = 0)	-	5	mA
V <sub>IO</sub>	Input or output range	-0.50	6.5	V
V <sub>CC</sub>	Supply voltage	-0.50	6.5	V
V <sub>ESD</sub>	Electrostatic discharge voltage (human body model)(3)	-4000	4000	V

<sup>1.</sup> Compliant with JEDEC Std J-STD-020C (for small body, Sn-Pb or Pb assembly), the ST ECOPACK® 7191395 specification, and the European directive on Restrictions on Hazardous Substances (RoHS) 2002/95/EU.

<sup>2.</sup>  $T_{LEAD}$  max must not be applied for more than 10 s.

<sup>3.</sup> AEC-Q100-002 (compliant with JEDEC Std JESD22-A114, C1 = 100 pF, R1 = 1500  $\Omega$ , R2 = 500  $\Omega$ ).

### 6 DC and AC parameters

This section summarizes the operating and measurement conditions, and the DC and AC characteristics of the device. The parameters in the DC and AC characteristic tables that follow are derived from tests performed under the measurement conditions summarized in the relevant tables. Designers should check that the operating conditions in their circuit match the measurement conditions when relying on the quoted parameters.

Table 6. Operating conditions (M24Cxx-W)

Symbol	Parameter	Min.	Max.	Unit
V <sub>CC</sub>	Supply voltage	2.5	5.5	V
т	Ambient operating temperature (device grade 6)	-40	85	°C
T <sub>A</sub>	Ambient operating temperature (device grade 3)	-40	125	Ĉ

Table 7. Operating conditions (M24Cxx-R)

Symbol	Parameter	Min.	Max.	Unit
V <sub>CC</sub>	Supply voltage	1.8	5.5	V
T <sub>A</sub>	Ambient operating temperature	-40	85	Ĉ

Table 8. Operating conditions (M24Cxx-F)

Symbol	Parameter	Min.	Max.	Unit
V <sub>CC</sub>	Supply voltage	1.7	5.5	V
T <sub>A</sub>	Ambient operating temperature	-20	85	C

Table 9. DC characteristics (M24Cxx-W, device grade 6)

Symbol	Parameter	Test conditions (in addition to those in <i>Table 6</i> )		Max.	Unit
ILI	Input leakage current (SCL, SDA, E0, E1,and E2)	$V_{IN} = V_{SS}$ or $V_{CC}$ , device in Standby mode		± 2	μΑ
I <sub>LO</sub>	Output leakage current	$V_{OUT} = V_{SS}$ or $V_{CC}$ , SDA in Hi-Z		± 2	μΑ
I <sub>CC</sub> Supply current	Supply current	$V_{CC} = 5 \text{ V}, f_{c} = 400 \text{ kHz}$ (rise/fall time < 50 ns)		2	mA
	Supply current	$V_{CC} = 2.5 \text{ V}, f_{c} = 400 \text{ kHz}$ (rise/fall time < 50 ns)		1	mA
I <sub>CC1</sub>	Standby supply current	Device not selected <sup>(1)</sup> , $V_{IN} = V_{SS}$ or $V_{CC}$ , for 2.5 V < $V_{CC} \le 5.5$ V		1	μΑ
V <sub>IL</sub>	Input low voltage (SDA, SCL, WC)		-0.45	0.3V <sub>CC</sub>	V

Table 9. DC characteristics (M24Cxx-W, device grade 6)

Symbo	Parameter	Test conditions (in addition to those in <i>Table 6</i> )	Min.	Max.	Unit
V <sub>IH</sub>	Input high voltage (SDA, SCL, WC)		0.7V <sub>CC</sub>	V <sub>CC</sub> +1	٧
V <sub>OL</sub>	Output low voltage	$I_{OL}$ = 2.1 mA when $V_{CC}$ = 2.5 V or $I_{OL}$ = 3 mA when $V_{CC}$ = 5.5 V		0.4	٧

The device is not selected after a power-up, after a read command (after the Stop condition), or after the completion of the internal write cycle t<sub>W</sub> (t<sub>W</sub> is triggered by the correct decoding of a write command).

Table 10. DC characteristics (M24Cxx-W, device grade 3)

Symbol	Parameter	Test condition (in addition to those in <i>Table 6</i> )	Min.	Max.	Unit
ILI	Input leakage current (SCL, SDA, E0, E1,and E2)	$V_{IN} = V_{SS}$ or $V_{CC}$ , device in Standby mode		± 2	μΑ
I <sub>LO</sub>	Output leakage current	$V_{OUT} = V_{SS}$ or $V_{CC}$ , SDA in Hi-Z		± 2	μΑ
1	Supply current	$V_{CC} = 5 \text{ V, } f_{C} = 400 \text{ kHz}$ (rise/fall time < 50 ns)		3	mA
I <sub>CC</sub>		$V_{CC}$ = 2.5 V, $f_C$ = 400 kHz (rise/fall time < 50 ns)		3	mA
	Standby supply current	Device not selected <sup>(1)</sup> , $V_{IN} = V_{SS}$ or $V_{CC}$ , $V_{CC} = 5 V$		5	μΑ
I <sub>CC1</sub>		Device not selected <sup>(1)</sup> , V <sub>IN</sub> = V <sub>SS</sub> or V <sub>CC</sub> , V <sub>CC</sub> = 2.5 V		2	μΑ
V <sub>IL</sub>	Input low voltage (SDA, SCL, $\overline{WC}$ )		-0.45	0.3V <sub>CC</sub>	>
V <sub>IH</sub>	Input high voltage (SDA, SCL, WC)		0.7V <sub>CC</sub>	V <sub>CC</sub> +1	>
V <sub>OL</sub>	Output low voltage	$I_{OL}$ = 2.1 mA when $V_{CC}$ = 2.5 V or $I_{OL}$ = 3 mA when $V_{CC}$ = 5.5 V		0.4	٧

The device is not selected after a power-up, after a read command (after the Stop condition), or after the completion of the internal write cycle t<sub>W</sub> (t<sub>W</sub> is triggered by the correct decoding of a write command).

Table 11. DC characteristics (M24Cxx-R)

Symbol	Parameter	Test condition (in addition to those in <i>Table 7</i> )	Min.	Max.	Unit
ILI	Input leakage current (SCL, SDA, E0, E1,and E2)	$V_{IN} = V_{SS}$ or $V_{CC}$ , device in Standby mode		± 2	μА
I <sub>LO</sub>	Output leakage current	$V_{OUT} = V_{SS}$ or $V_{CC}$ , SDA in Hi-Z		± 2	μΑ
I <sub>CC</sub>	Supply current	$V_{CC}$ = 1.8 V, $f_c$ = 400 kHz (rise/fall time < 50 ns)		0.8	mA
I <sub>CC1</sub>	Standby supply current	Device not selected <sup>(1)</sup> , $V_{IN} = V_{SS}$ or $V_{CC}$ , $V_{CC} = 1.8 \text{ V}$		1	μА

Table 11. DC characteristics (M24Cxx-R)

Symbol	Parameter	Test condition (in addition to those in <i>Table 7</i> )	Min.	Max.	Unit
V	Input low voltage (SDA,	2.5 V ≤ V <sub>CC</sub>	-0.45	0.3 V <sub>CC</sub>	V
V <sub>IL</sub>	SCL, WC)	1.8 V ≤ V <sub>CC</sub> < 2.5 V	-0.45	0.25 V <sub>CC</sub>	V
V <sub>IH</sub>	Input high voltage (SDA, SCL, WC)		0.7V <sub>CC</sub>	V <sub>CC</sub> +1	٧
V <sub>OL</sub>	Output low voltage	$I_{OL} = 0.7 \text{ mA}, V_{CC} = 1.8 \text{ V}$		0.2	V

<sup>1.</sup> The device is not selected after a power-up, after a read command (after the Stop condition), or after the completion of the internal write cycle t<sub>W</sub> (t<sub>W</sub> is triggered by the correct decoding of a write command).

Table 12. DC characteristics (M24Cxx-F)

Symbol	Parameter	Test condition (in addition to those in <i>Table 8</i> )	Min.	Max.	Unit
ILI	Input leakage current (SCL, SDA, E0, E1,and E2)	V <sub>IN</sub> = V <sub>SS</sub> or V <sub>CC</sub> , device in Standby mode		± 2	μΑ
I <sub>LO</sub>	Output leakage current	$V_{OUT} = V_{SS}$ or $V_{CC}$ , SDA in Hi-Z		± 2	μΑ
I <sub>CC</sub>	Supply current	$V_{CC}$ = 1.7 V, $f_c$ = 400 kHz (rise/fall time < 50 ns)		0.8	mA
I <sub>CC1</sub>	Standby supply current	Device not selected <sup>(1)</sup> , $V_{IN} = V_{SS}$ or $V_{CC}$ , $V_{CC} = 1.7$ V		1	μА
V	Input low voltage (SDA, SCL, WC)	2.5 V ≤ V <sub>CC</sub>	-0.45	0.3 V <sub>CC</sub>	V
V <sub>IL</sub>		1.7 V ≤ V <sub>CC</sub> < 2.5 V	-0.45	0.25 V <sub>CC</sub>	٧
V <sub>IH</sub>	Input high voltage (SDA, SCL, WC)		0.7V <sub>CC</sub>	V <sub>CC</sub> +1	V
V <sub>OL</sub>	Output low voltage	$I_{OL} = 0.7 \text{ mA}, V_{CC} = 1.7 \text{ V}$		0.2	V

The device is not selected after a power-up, after a read command (after the Stop condition), or after the completion of the internal write cycle t<sub>W</sub> (t<sub>W</sub> is triggered by the correct decoding of a write command).

Table 13. AC measurement conditions

Symbol	Parameter Mir		Max.	Unit
C <sub>L</sub>	Load capacitance	100		pF
	Input rise and fall times	50		ns
	Input levels	0.2V <sub>CC</sub> to 0.8V <sub>CC</sub>		V
	Input and output timing reference levels	0.3V <sub>CC</sub> to 0.7V <sub>CC</sub>		V

Figure 11. AC measurement I/O waveform

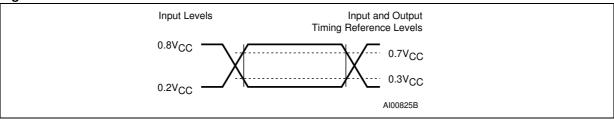


Table 14. Input parameters

Symbol	Parameter <sup>(1)</sup>	Test condition	Min.	Max.	Unit
C <sub>IN</sub>	Input capacitance (SDA)			8	pF
C <sub>IN</sub>	Input capacitance (other pins)			6	pF
Z <sub>WCL</sub>	WC input impedance	V <sub>IN</sub> < 0.3 V	15	70	kΩ
Z <sub>WCH</sub>	WC input impedance	V <sub>IN</sub> > 0.7V <sub>CC</sub>	500		kΩ
t <sub>NS</sub>	Pulse width ignored (input filter on SCL and SDA)	Single glitch		100	ns

<sup>1.</sup> Characterized only.

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Table 15. AC characteristics at 400 kHz (I<sup>2</sup>C Fast-mode) (M24Cxx-W, M24Cxx-R, M24Cxx-F)

	Test conditions specified in either Table 6, Table 7 or Table 8 and Table 13						
Symbol	Alt.	Parameter	Min.	Max.	Unit		
f <sub>C</sub>	f <sub>SCL</sub>	Clock frequency	-	400	kHz		
t <sub>CHCL</sub>	t <sub>HIGH</sub>	Clock pulse width high	600	-	ns		
t <sub>CLCH</sub>	$t_{LOW}$	Clock pulse width low	1300	-	ns		
t <sub>XH1XH2</sub> <sup>(1)</sup>	t <sub>R</sub>	Input signal rise time	20	300	ns		
t <sub>XL1XL2</sub> <sup>(1)</sup>	t <sub>F</sub>	Input signal fall time	20	300	ns		
t <sub>DL1DL2</sub> <sup>(2)</sup>	t <sub>F</sub>	SDA fall time	20	300	ns		
t <sub>DXCX</sub>	t <sub>SU:DAT</sub>	Data in setup time	100	-	ns		
t <sub>CLDX</sub>	t <sub>HD:DAT</sub>	Data in hold time	0	-	ns		
t <sub>CLQX</sub>	t <sub>DH</sub>	Data out hold time	200	-	ns		
t <sub>CLQV</sub> (3)	t <sub>AA</sub>	Clock low to next data valid (access time)	200	900	ns		
t <sub>CHDX</sub> <sup>(4)</sup>	t <sub>SU:STA</sub>	Start condition setup time	600	-	ns		
t <sub>DLCL</sub>	t <sub>HD:STA</sub>	Start condition hold time	600	-	ns		
t <sub>CHDH</sub>	t <sub>SU:STO</sub>	Stop condition setup time	600	-	ns		
t <sub>DHDL</sub>	t <sub>BUF</sub>	Time between Stop condition and next Start condition	1300	-	ns		
t <sub>W</sub>	t <sub>WR</sub>	Write time	-	5	ms		

Values recommended by the I<sup>2</sup>C bus Fast-mode specification for a robust design of the I<sup>2</sup>C bus application. Note that the M24xxx devices decode correctly input rise or fall times from 1 ns up to 1 ms.

<sup>2.</sup> Characterized only.

<sup>3.</sup> To avoid spurious Start and Stop conditions, a minimum delay is placed between SCL=1 and the falling or rising edge of SDA.

<sup>4.</sup> For a reStart condition, or following a Write cycle.

Table 16. AC characteristics at 100 kHz (I<sup>2</sup>C Standard-mode)<sup>(1)</sup> (M24Cxx-W, M24Cxx-R, M24Cxx-F)

	Test conditions specified in either Table 6, Table 7 or Table 8 and Table 13						
Symbol	Alt.	Parameter	Min.	Max.	Unit		
f <sub>C</sub>	f <sub>SCL</sub>	Clock frequency	-	100	kHz		
t <sub>CHCL</sub>	t <sub>HIGH</sub>	Clock pulse width high	4	-	μs		
t <sub>CLCH</sub>	t <sub>LOW</sub>	Clock pulse width low	4.7	-	μs		
t <sub>XH1XH2</sub>	t <sub>R</sub>	Input signal rise time	-	1	μs		
t <sub>XL1XL2</sub>	t <sub>F</sub>	Input signal fall time	-	300	ns		
t <sub>DL1DL2</sub> <sup>(2)</sup>	t <sub>F</sub>	SDA fall time	-	300	ns		
t <sub>DXCX</sub>	t <sub>SU:DAT</sub>	Data in setup time	250	-	ns		
t <sub>CLDX</sub>	t <sub>HD:DAT</sub>	Data in hold time	0	-	ns		
t <sub>CLQX</sub>	t <sub>DH</sub>	Data out hold time	200	-	ns		
t <sub>CLQV</sub> (3)	t <sub>AA</sub>	Clock low to next data valid (access time)	200	3450	ns		
t <sub>CHDX</sub> <sup>(4)</sup>	t <sub>SU:STA</sub>	Start condition setup time	4.7	-	μs		
t <sub>DLCL</sub>	t <sub>HD:STA</sub>	Start condition hold time	4	-	μs		
t <sub>CHDH</sub>	t <sub>SU:STO</sub>	Stop condition setup time	4	-	μs		
t <sub>DHDL</sub>	t <sub>BUF</sub>	Time between Stop condition and next Start condition	4.7	-	μs		
t <sub>W</sub>	t <sub>WR</sub>	Write time	-	5	ms		

Values recommended by the I<sup>2</sup>C bus Standard-mode specification for a robust design of the I<sup>2</sup>C bus application. Note that the M24xxx devices decode correctly faster timings as specified in *Table 15: AC characteristics at 400 kHz (I2C Fast-mode) (M24Cxx-W, M24Cxx-R, M24Cxx-F).*

<sup>2.</sup> Characterized only.

<sup>3.</sup> To avoid spurious Start and Stop conditions, a minimum delay is placed between SCL=1 and the falling or rising edge of SDA.

<sup>4.</sup> For a reStart condition, or following a Write cycle.